

# **Notice of References Cited**

Application/Control No.

09/146,839

Applicant(s)/Patent Under  
Reexamination  
SRINIVASAN ET AL.

Examiner

Anh D. Mai

Art Unit

2814

Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-5,462,899	10-1995	Ikeda, Yasuo	438/790
X	B	US-5,521,424	05-1996	Ueno et al.	257/632
X	C	US-5,610,105	03-1997	Vines et al.	438/789
X	D	US-5,633,211	05-1997	Imai et al.	438/760
X	E	US-5,648,175	07-1997	Russell et al.	428/472.3
X	F	US-5,908,672	06-1999	Ryu et al.	427/574
X	G	US-5,976,973	11-1999	Ohira et al.	438/645
X	H	US-6,009,827	01-2000	Robles et al.	118/723R
X	I	US-6,121,163	09-2000	Gupta et al.	438/788
X	J	US-6,121,164	09-2000	Yieh et al.	438/790
X	K	US-6,159,870	12-2000	Chakravarti et al.	438/784
X	L	US-6,191,026	02-2001	Rana et al.	438/624
	M	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
X	N	EP-860869 A1	08-1998	European	Matsuki et al.	H01L 21/316
X	O	JP-09-064029	03-1997	Japan	Maeda et al.	H01L 21/316
X	P	JP-10-242142	09-1998	Japan	Matsuki et al.	H01L 21/316
X	Q	TW-275699	05-1996	Taiwan	Hwang et al.	H01L 21/205
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.